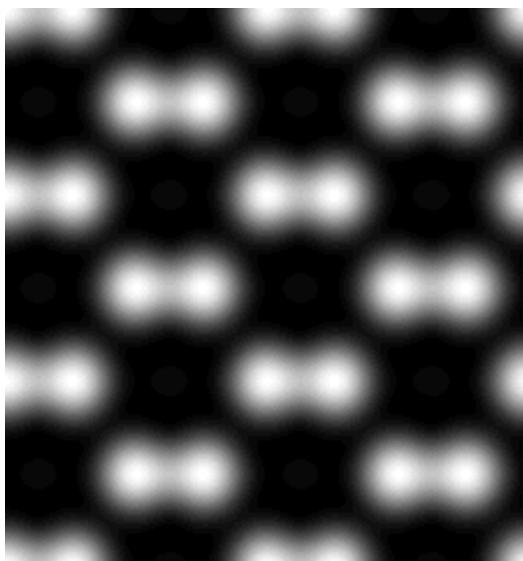


*Optional
Function*

STEM

for *MacHREM*TM / *WinHREM*TM

Scanning Transmission Electron Microscope Image Simulation Program



Simulated HAADF image for GaAs [011]

This optional function adds the capability for simulating high-resolution scanning transmission electron microscope images to the *MacHREM*TM / *WinHREM*TM program suite. Using this program you can simulate bright-field images, dark-field images and high-angle annular dark-field (HAADF) images by using the FFT multislice technique on a personal computer.

- User Friendly Graphical Interface

Even a novice user can easily generate his/her data and perform computation.

- Reliable and Efficient Algorithm

Dynamical electron interaction is efficiently estimated by using the FFT multislice technique including an absorption potential.

- High Quality Image Output

All images are generated with a standard image format of Windows/Mac OS. Therefore, high quality images can be printed from them, and they can be imported into another application.

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REFERENCE: K. Ishizuka: A practical approach for STEM image simulation based on the FFT multislice method, *Ultramicroscopy* 90 (2001) 71-83.